







# Carbon deposition on beryllium substrates and subsequent delamination

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# Introduction

Pure beryllium, carbon and tungsten parts will be used as plasma facing components in future fusion devices. However, mixed layers and compound formation will occur in the component surfaces during reactor operation due to erosion, re-/co-deposition and heat-load events. As result, the properties of the exposed surfaces will evolve in time and depend on the phase transformations arising from the interaction with the plasma [1,2,3]. The experimental results also evidence that re-/codeposits tend to flake and peel-off from the substrate [4,5] and contribute to the formation of dust agglomerates in the plasma [5]. The present work studied the Be-C system and shows that the compound formation promotes by itself the occurrence of dust emission events.

The Be-C system was studied previously by depositing C thin layers in Be substrates. The formation of beryllium carbide (Be<sub>2</sub>C) starts at about 557 K at the interface and is strongly promoted at higher temperatures [2,3]. A fast formation of beryllium oxide (BeO) at the surface is also evident in the same temperature range [2,3]. Heat loads can induce a compressive stress and the blistering of deposited thin films [7]. Compounds are easily formed at the blisters due to their lower thermal conductivity. The presence of distinct phases presenting different lattice parameters and thermal expansion coefficients lead to the fracture and removal of the blisters in the surface. The phenomena could be visualised by following the annealing route via electron microscopy.

# Sample preparation

#### 120 nm carbon films were evaporated in pure beryllium plates

with an electron beam evaporator

polished beryllium plates (Goodfellow, 99.8+ at.% / SiC paper 4000 mesh) graphite rod (99.0+ at.%) used as carbon source

#### Samples were annealed

in the 373 to 1073 K range during 90 min with temperature steps of 100 K

# Analytical techniques

Rutherford Backscattering (RBS)

X-ray Diffraction (XRD) - grazing geometry

Scanning Electron Microscopy (SEM)

Secondary Electron (SE) and Backscattered Electron (BSE) analysis Energy-dispersive X-ray spectroscopy (EDS)

# **Results and discussion**

## Rutherford Backscattering (RBS) and X-ray Diffraction (XRD)

Slight modifications of the Be, C and O RBS yields between 373 and 773 K.

• The Be-C reaction becomes very fast at higher temperatures and it is complete after the annealing at 1073 K.

· Be seems to difuse through the carbide layer and oxidises at the surface.

· SEM analysis detected a blistered and an unblistered zone in the sample annealed at 973 K (see Fig.3.c). RBS data reveal that the blistered zone presents a higher O content.

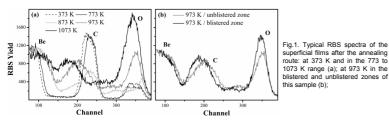
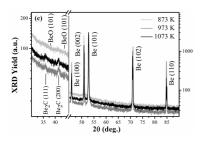


Table 1. Composition of the superficial layers revealed by RBS (100 nm of pure C is equivalent to  $1130 \times 10^{15}$  at./cm<sup>2</sup>).

Annealing temperature	Thickness of the	Elemental content in the film for	
(K)	reactive layer (nm)	Be (1015 at./cm2)	O (1015 at./cm2)
373	118	0	121
773	117	94	138
873	330	2891	217
973	392	3060	455
4070	504	4000	002



- The presence of  $\mathsf{Be}_2\mathsf{C}$  is confirmed in the films annealed above 873 K by XRD analysis

· However, the BeO signature is not visible in the spectra, suggesting a different preferencial location for the BeO component in the films.

Fig.2. Be<sub>2</sub>C signature in the X-ray diffraction pattern at higher temperatures (c).

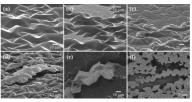
## Microstructural analysis by SEM (SE, BSE and EDS mapping)

• The annealing route induced the formation of telephone-cord like blisters resulting from a thermal compressive stress of the deposited films (Fig.3).

· A carbide formation reaction front became apparent at 873 K and higher temperatures (see Fig.3b to 3d).

• The blisters delaminates from the films annealed above 873 K (Fig.3e and 3f), whereas the films annealed at lower temperatures remain unchanged.

· SE/BSE images in Fig.4 confirm that C is the only component of the films after annealing at 773 K (see Fig.4c), and BeO formation starts at 873 K due to Be diffusion through the C layer (see Fig.4f).



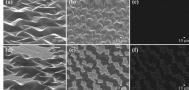
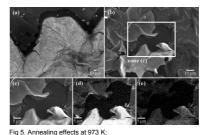


Fig. 3. SE images of the blisters formed in the films after the annealing route at 773 (a), 873 (b), 973 (c) and 1073 K (d), BSE images revealing a long term delamination behaviour of the films annealed at 973 (e) and at 1073 K (f).



Ing or number of precipitation in a blister (BSE image) presenting the lamellar structure with both BeO and Be<sub>2</sub>C (a), detamination event (SE image) (b), detail of Fig.3.b (c) and corresponding EDS maps for oxygen (d) and carbon (e).

# Conclusions and future work

From the present work becomes evident that the formation of compounds in the C-Be (and O) system promotes by itself the delamination of re-deposited layers.

It is foreseen the use of carbon parts in the divertor components of future fusion reactors [1,5] and it will be advantageous to study the reverse Be-C system by depositing and annealing Be films in graphite substrates.

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Fig. 4. Films surfaces after annealing: 773 K: SE image (a), equivalent SE (b) and BSE (c) top views; 873 K: SE image (d), equivalent SE (e) and BSE (f) top views.

. The oxidation of the films evolves at the blisters in a lamellar (DP) structure presenting the BeO and Be<sub>2</sub>C phases (BSE image in Fig.5a).

• The BeO and Be<sub>2</sub>C crystallographic structures are too distinct and promote the delamination events (see the EDS maps for O and C in Fig.5.d and 5e).

BeO (and Be) - hexagonal structure a = 272.3 pm, c = 437.6 pm (a = 228.5 pm, c = 358.1 pm) Be<sub>2</sub>C - cubic structure

a = 356.3 pm